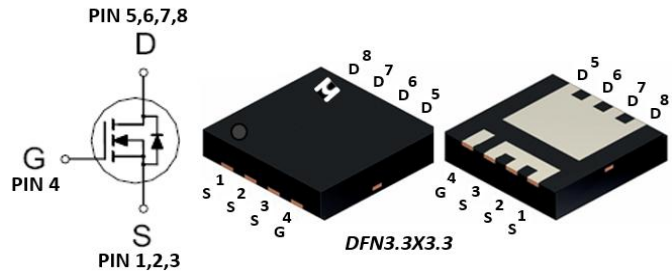


Single N-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

	N-CH
BV_{DSS}	80V
$R_{DS(on)(MAX)} V_{GS}=10V$	7mΩ
$R_{DS(on)(MAX)} V_{GS}=4.5V$	10mΩ
$I_D @ T_C=25^{\circ}C$	113A
$I_D @ T_A=25^{\circ}C$	20A

Pin Description:



Single N Channel MOSFET

UIS, Rg 100% Tested

RoHS & Halogen Free & TSCA Compliant



ABSOLUTE MAXIMUM RATINGS ($T_C = 25^{\circ}C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V_{GS}	± 20	V
Continuous Drain Current	$T_C = 25^{\circ}C$	I_D	113	A
	$T_C = 100^{\circ}C$		71	
Continuous Drain Current	$T_A = 25^{\circ}C$	I_D	20	
	$T_A = 70^{\circ}C$		16	
Pulsed Drain Current ¹		I_{DM}	274	
Avalanche Current		I_{AS}	50	mJ
Avalanche Energy	$L = 0.1mH$	EAS	125	
Repetitive Avalanche Energy ²	$L = 0.05mH$	EAR	63	
Power Dissipation	$T_C = 25^{\circ}C$	P_D	178	W
	$T_C = 100^{\circ}C$		71	
Power Dissipation	$T_A = 25^{\circ}C$	P_D	6.0	W
	$T_A = 70^{\circ}C$		4	
Operating Junction & Storage Temperature Range		T_j, T_{stg}	-55 to 150	$^{\circ}C$

100% UIS testing in condition of $V_D=60V$, $L=0.1mH$, $V_G=10V$, $I_L=30A$, $R_G=25\Omega$, Rated $V_{DS}=80V$ N-CH

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE		SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case		$R_{\theta JC}$		0.7	$^{\circ}C/W$
Junction-to-Ambient ^{3,4}	$t \leq 10s$	$R_{\theta JA}$		21	
	Steady-State	$R_{\theta JA}$		54	

¹Pulse width limited by maximum junction temperature.

²Duty cycle < 1%

³The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^{\circ}C$.

⁴Guarantee by Engineering test

■ ELECTRICAL CHARACTERISTICS (T_J = 25 °C, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage ⁴	V _{(BR)DSS}	V _{GS} = 0V, I _D = 250uA	80			V
Gate Threshold Voltage ⁴	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250μA	1.2	1.8	2.5	
Gate-Body Leakage ⁴	I _{GSS}	V _{DS} = 0V, V _{GS} = ±20V			±100	nA
Zero Gate Voltage Drain Current ⁴	I _{DSS}	V _{DS} = 80V, V _{GS} = 0V			1	μA
		V _{DS} =80V, V _{GS} =0V, T _J = 125 °C			25	
On-State Drain Current ¹	I _{D(ON)}	V _{DS} = 10V, V _{GS} = 10V	113			A
Drain-Source On-State Resistance ^{1,4}	R _{DS(ON)}	V _{GS} = 10V, I _D = 20A		6.5	7	mΩ
Drain-Source On-State Resistance ^{1,4}	R _{DS(ON)}	V _{GS} = 4.5V, I _D = 10A		8.5	10	mΩ
Forward Transconductance ¹	g _{fs}	V _{DS} = 5V, I _D = 20A		72		S
DYNAMIC						
Input Capacitance ⁵	C _{iss}	V _{GS} = 0V, V _{DS} = 40V, f = 1MHz		1570		pF
Output Capacitance ⁵	C _{oss}			272		
Reverse Transfer Capacitance ⁵	C _{rss}			45		
Gate Resistance ^{4,5}	R _g	f = 1MHz		1.6		Ω
Total Gate Charge ^{1,2,5}	Q _g (V _{GS} =10V)	V _{DS} = 40V, V _{GS} = 10V, I _D = 20A		29		nC
Total Gate Charge ^{1,2,5}	Q _g (V _{GS} =4.5V)			14		
Gate-Source Charge ^{1,2,5}	Q _{gs}			7		
Gate-Drain Charge ^{1,2,5}	Q _{gd}			6		
Turn-On Delay Time ^{1,2,5}	t _{d(on)}	V _{DS} = 40V, V _{GS} = 10V, I _D = 5A , R _g = 3Ω		8		nS
Rise Time ^{1,2,5}	t _r			8		
Turn-Off Delay Time ^{1,2,5}	t _{d(off)}			37		
Fall Time ^{1,2,5}	t _f			20		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS						
Continuous Current	I _S				148	A
Pulsed Current ³	I _{SM}				274	
Forward Voltage ^{1,4}	V _{SD}	I _F = 20A, V _{GS} = 0V			1.2	V
Reverse Recovery Time ⁵	t _{rr}	I _F = 20A, dI _F /dt = 100A / μS		36		nS
Peak Reverse Recovery Current ⁵	I _{RM(REC)}			2		A
Reverse Recovery Charge ⁵	Q _{rr}			33		nC

¹Pulse test : Pulse Width ≤ 300 usec, Duty Cycle ≤ 2%.

²Independent of operating temperature.

³Pulse width limited by maximum junction temperature.

⁴Guarantee by FT test Item

⁵Guarantee by Engineering test

EMC will review datasheet by quarter, and update new version.



■ N-CH_TYPICAL CHARACTERISTICS

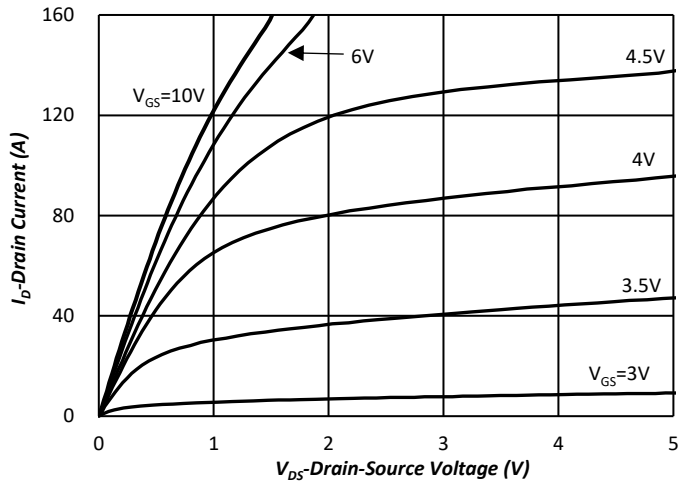


Fig.1 Typical Output Characteristics

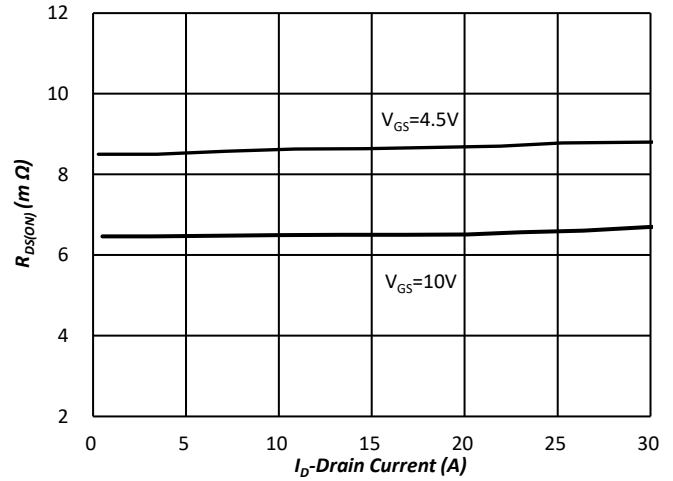


Fig.2 On-Resistance Variation with Drain Current and Gate Voltage

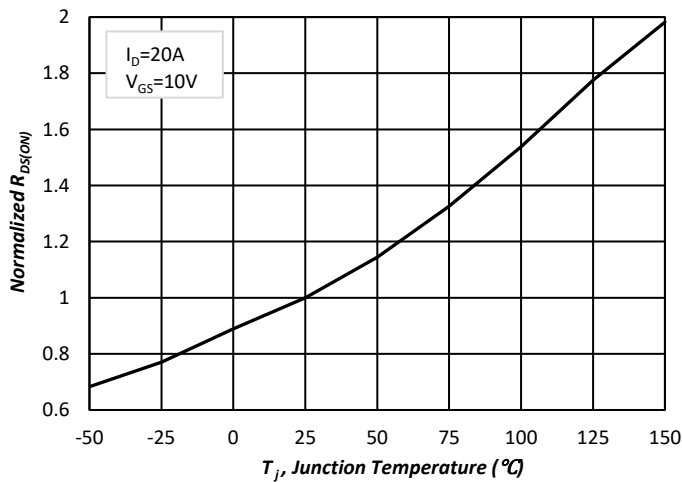


Fig.3 Normalized On-Resistance v.s. Junction Temperature

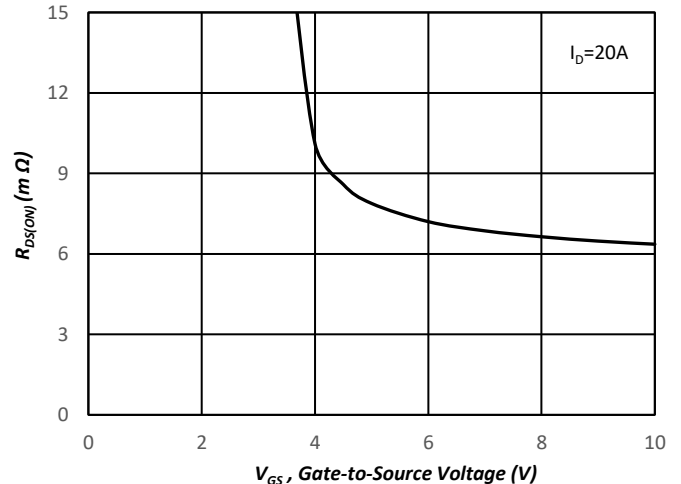


Fig.4 On-Resistance v.s. Gate Voltage

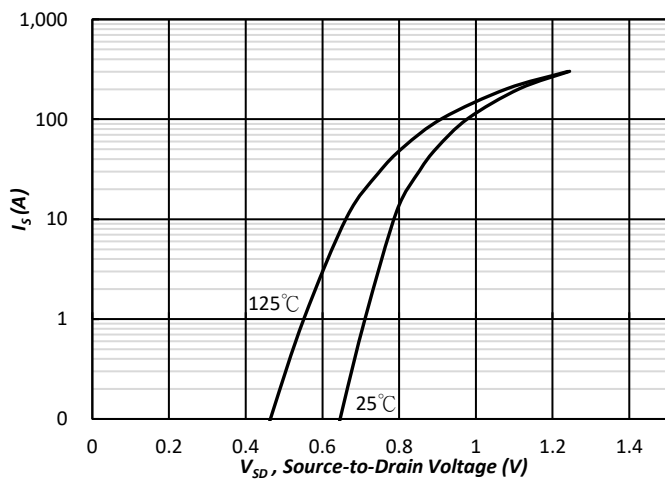


Fig.5 Forward Characteristic of Reverse Diode

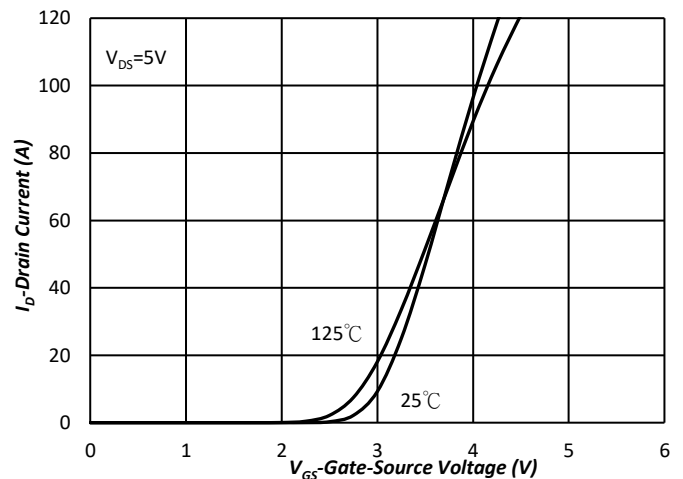


Fig.6 Transfer Characteristics

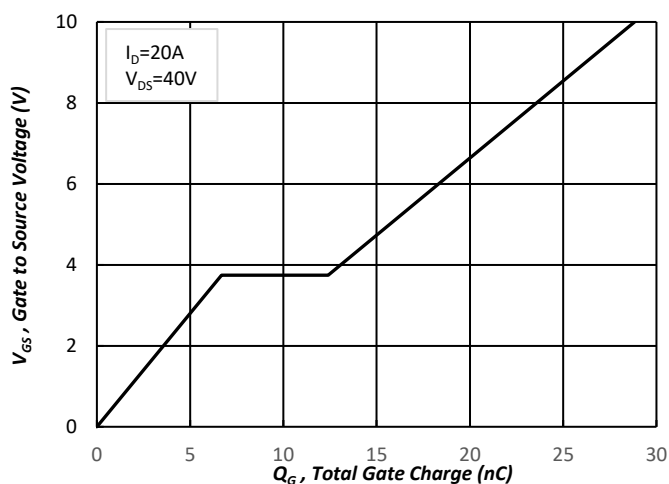


Fig.7 Gate Charge Characteristics

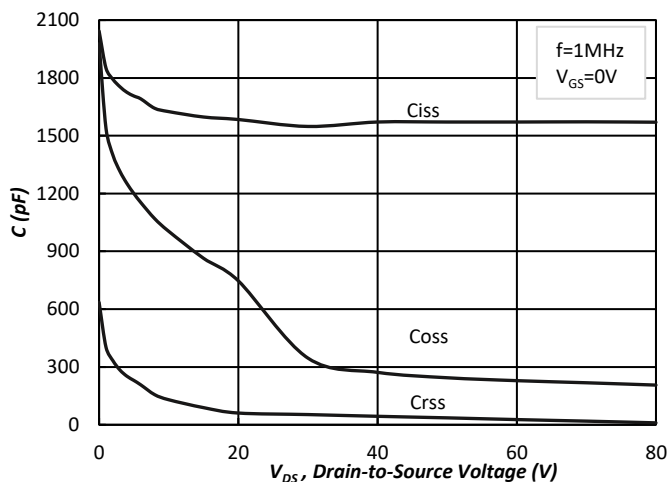


Fig.8 Typical Capacitance Characteristics

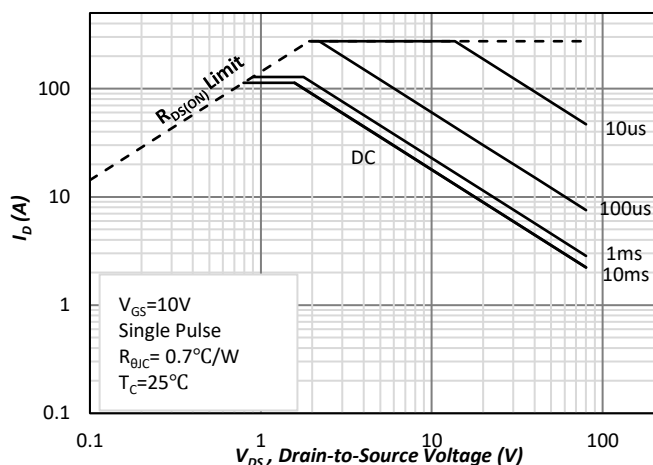


Fig.9. Maximum Safe Operating Area

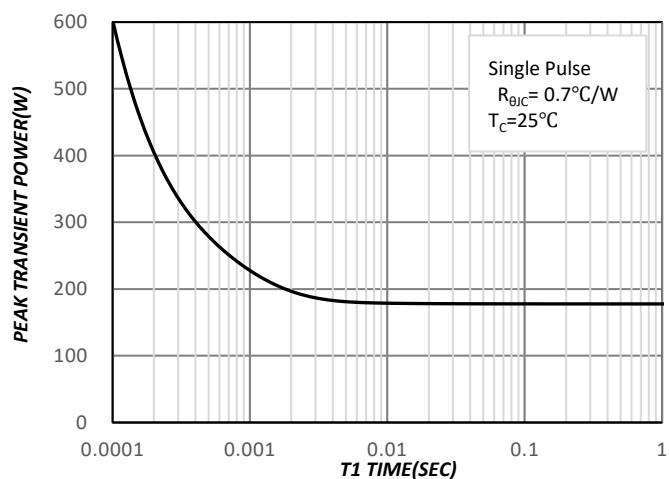


Fig.10. Single Pulse Maximum Power Dissipation

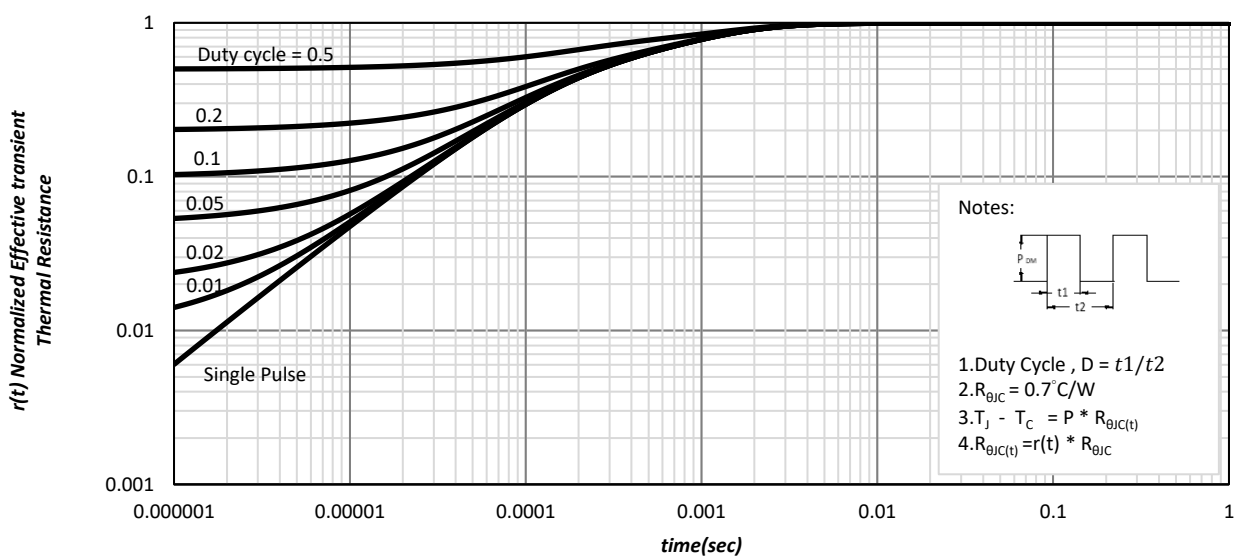


Fig.11. Effective Transient Thermal Impedance

Ordering & Marking Information:

Device Name: EMCB070N08VSCS for DFN 3.3X3.3



PIN 1

→ B070N08S: Device Name

→ ABCDEFG: Date Code

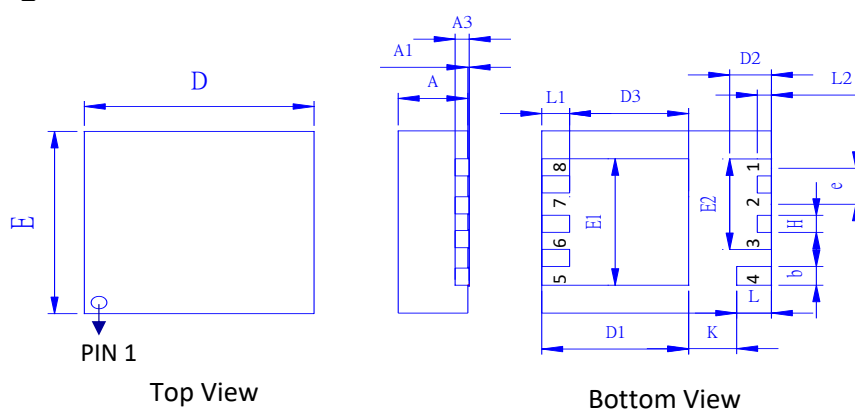
A: Assembly House

B: Year(A:2008 B:2009 C:2010....)

C: Month(A:01 B:02 C:03 D:04 E:05 F:06 G:07 H:08 I:09 J:10 K:11 L:12)

DEFG: Serial No.

Outline Drawing

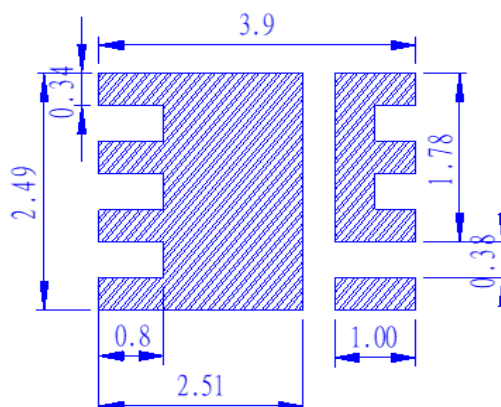


Dimension in mm

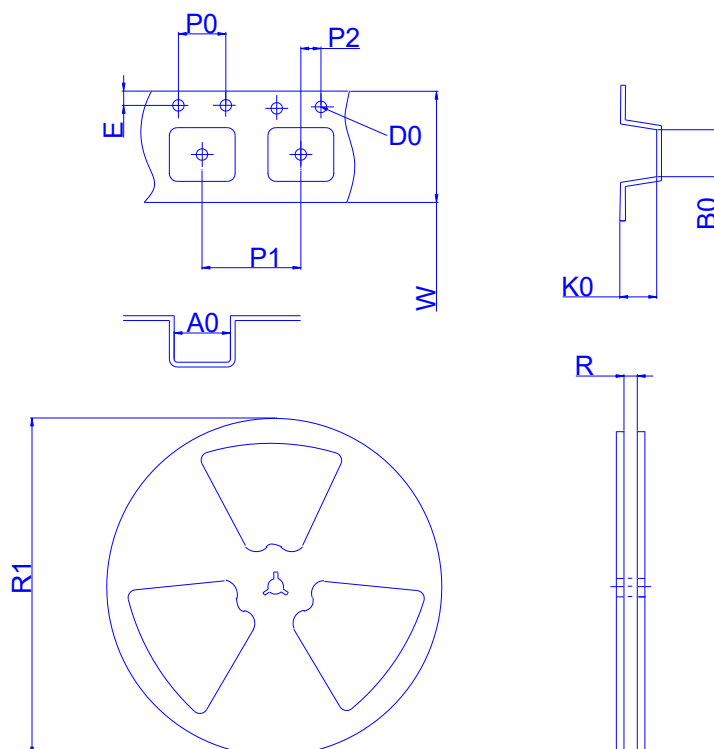
Dimension	A	A1	A3	b	D	E	D1	E1	E2	D3	e	H	L
Min	0.90	-	0.10	0.24	3.20	3.20	2.01	2.19	1.54	1.61	-	0.21	0.40
Typ.	1.00	0.02	-	-	3.30	3.30	2.11	2.29	1.64	-	0.65	0.31	0.55
Max	1.10	0.05	0.30	0.44	3.40	3.40	2.21	2.39	1.74	1.81	-	0.41	0.70

Dimension	L1	L2
Min	0.30	0.10
Typ.	0.40	0.20
Max	0.51	0.30

Footprint



◆ **Tape&Reel Information: 5000pcs/Reel**



Package	DFN3.3X3.3
Reel	13"
Device orientation	FEED DIRECTION

Dimension in mm

Dimension	Carrier tape									Reel	
	A0	B0	D0	E	K0	P0	P1	P2	W	R	R1
Typ.	3.6	3.6	1.55	1.7	1.2	4	8	2	12	12.4	330
±	0.3	0.3	0.2	0.2	0.2	0.1	0.1	0.1	1	2	2